Power MOSFET

30 V, 106 A, Single N-Channel, SO-8 FL

Features

- Integrated Schottky Diode
- Low R_{DS(on)} to Minimize Conduction Losses
- Low Capacitance to Minimize Driver Losses
- Optimized Gate Charge to Minimize Switching Losses
- These Devices are Pb-Free and are RoHS Compliant

Applications

- CPU Power Delivery
- Synchronous Rectification for DC-DC Converters
- Low Side Switching
- Telecom Secondary Side Rectification

MAXIMUM RATINGS (T_J = 25°C unless otherwise stated)

Da.ca			Cumbal	Value	I Imit
	meter		Symbol	Value	Unit
Drain-to-Source Volt			V_{DSS}	30	V
Gate-to-Source Volta	age		V_{GS}	±20	V
Continuous Drain Current R _{θJA}		T _A = 25°C	I _D	30	Α
(Note 1)		T _A = 85°C		22	
Power Dissipation $R_{\theta JA}$ (Note 1)		T _A = 25°C	P _D	3.13	W
Continuous Drain Current R _{θJA} ≤		T _A = 25°C	I _D	48	Α
10 sec		T _A = 85°C	1	34	
Power Dissipation $R_{\theta JA,} t \leq 10 \text{ sec}$	Steady	T _A = 25°C	P _D	7.7	W
Continuous Drain Current R _{BJA}	State	T _A = 25°C	I _D	22	Α
(Note 2)		T _A = 85°C		16	
Power Dissipation R _{0JA} (Note 2)		T _A = 25°C	P _D	1.7	W
Continuous Drain Current R _{0.IC}		T _C = 25°C	I _D	106	Α
(Note 1)		T _C = 85°C		76	
Power Dissipation R ₀ JC (Note 1)		T _C = 25°C	P _D	38	W
Pulsed Drain Current	t _p =10μs	T _A = 25°C	I _{DM}	320	А
Current limited by pac	ckage	T _A = 25°C	I _{Dmaxpkg}	100	Α
Operating Junction ar Temperature	nd Storage		T _J , T _{STG}	-55 to +150	°C
Source Current (Body	/ Diode)		I _S	54	Α
Drain to Source dV/dt		dV/dt	6	V/ns	
Single Pulse Drain–to–Source Avalanche Energy (V_{DD} = 50 V, V_{GS} = 10 V, I_L = 45 A_{pk} , L = 0.1 mH, R_G = 25 Ω)		EAS	101	mJ	
Lead Temperature for Soldering Purposes (1/8" from case for 10 s)		TL	260	°C	

Stresses exceeding Maximum Ratings may damage the device. Maximum Ratings are stress ratings only. Functional operation above the Recommended Operating Conditions is not implied. Extended exposure to stresses above the Recommended Operating Conditions may affect device reliability.

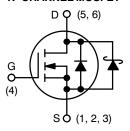


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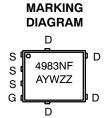
http://onsemi.com

V _{(BR)DSS}	R _{DS(ON)} MAX	I _D MAX
30 V	2.1 mΩ @ 10 V	100 4
30 V	3.1 mΩ @ 4.5 V	106 A

N-CHANNEL MOSFET







A = Assembly Location

Y = Year
W = Work Week
ZZ = Lot Traceability

ORDERING INFORMATION

Device	Package	Shipping [†]
NTMFS4983NFT1G	SO-8FL (Pb-Free)	1500 / Tape & Reel
NTMFS4983NFT3G	SO-8FL (Pb-Free)	5000 / Tape & Reel

†For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

*For additional information on our Pb–Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

THERMAL RESISTANCE MAXIMUM RATINGS

Parameter	Symbol	Value	Unit
Junction-to-Case (Drain)	$R_{ heta JC}$	3.3	
Junction-to-Ambient - Steady State (Note 1)	$R_{\theta JA}$	40	°C/W
Junction-to-Ambient - Steady State (Note 2)	$R_{\theta JA}$	74	*C/VV
Junction-to-Ambient - t ≤ 10 sec	$R_{ hetaJA}$	16.3	

- Surface-mounted on FR4 board using 1 sq-in pad, 2 oz Cu.
 Surface-mounted on FR4 board using the minimum recommended pad size of 100 mm².

ELECTRICAL CHARACTERISTICS (T_{.1} = 25°C unless otherwise specified)

Parameter	Symbol	Test Condition		Min	Тур	Max	Unit
OFF CHARACTERISTICS							
Drain-to-Source Breakdown Voltage	V _{(BR)DSS}	V _{GS} = 0 V, I _D = 1.0 mA		30			V
Drain-to-Source Breakdown Voltage Temperature Coefficient	V _{(BR)DSS} / T _J	I _D = 10 mA, referenced to 25°C			15		mV/°C
Zero Gate Voltage Drain Current	I _{DSS}	V _{GS} = 0 V, V _{DS} = 24 V	T _J = 25°C			500	μΑ
Gate-to-Source Leakage Current	I _{GSS}	V _{DS} = 0 V, V _{GS} = ±20 V				±100	nA
ON CHARACTERISTICS (Note 3)	-						
Gate Threshold Voltage	V _{GS(TH)}	V _{GS} = V _{DS} , I _D = 1.0 mA		1.2	1.7	2.3	V
Negative Threshold Temperature Coefficient	V _{GS(TH)} /T _J	I _D = 10 mA, referenced to 25°C			5.0		mV/°C
Drain-to-Source On Resistance	R _{DS(on)}	V _{GS} = 10 V	I _D = 30 A		1.6	2.1	mΩ
			I _D = 15 A		1.6		
		V _{GS} = 4.5 V	I _D = 30 A		2.5	3.1	
			I _D = 15 A		2.5		
Forward Transconductance	9FS	V _{DS} = 1.5 V, I _D	= 15 A		60		S
CHARGES AND CAPACITANCES				•			
Input Capacitance	C _{ISS}	V _{GS} = 0 V, f = 1 MHz, V _{DS} = 15 V			3250		pF
Output Capacitance	C _{OSS}				1340		
Reverse Transfer Capacitance	C _{RSS}				90		
Total Gate Charge	Q _{G(TOT)}				22.6		1
Threshold Gate Charge	Q _{G(TH)}	$V_{GS} = 4.5 \text{ V}, V_{DS} = 15 \text{ V}; I_D = 30 \text{ A}$			2.9		nC
Gate-to-Source Charge	Q _{GS}				7.0		
Gate-to-Drain Charge	Q _{GD}				6.9		
Total Gate Charge	Q _{G(TOT)}	V _{GS} = 10 V, V _{DS} = 15 V, I _D = 30 A			47.9		nC
SWITCHING CHARACTERISTICS (Note 4)						-	
Turn-On Delay Time	t _{d(ON)}	V_{GS} = 4.5 V, V_{DS} = 15 V, I_{D} = 15 A, R_{G} = 3.0 Ω			13.5		ns
Rise Time	t _r				24.9		
Turn-Off Delay Time	t _{d(OFF)}				28.7		
Fall Time	t _f				10.7		

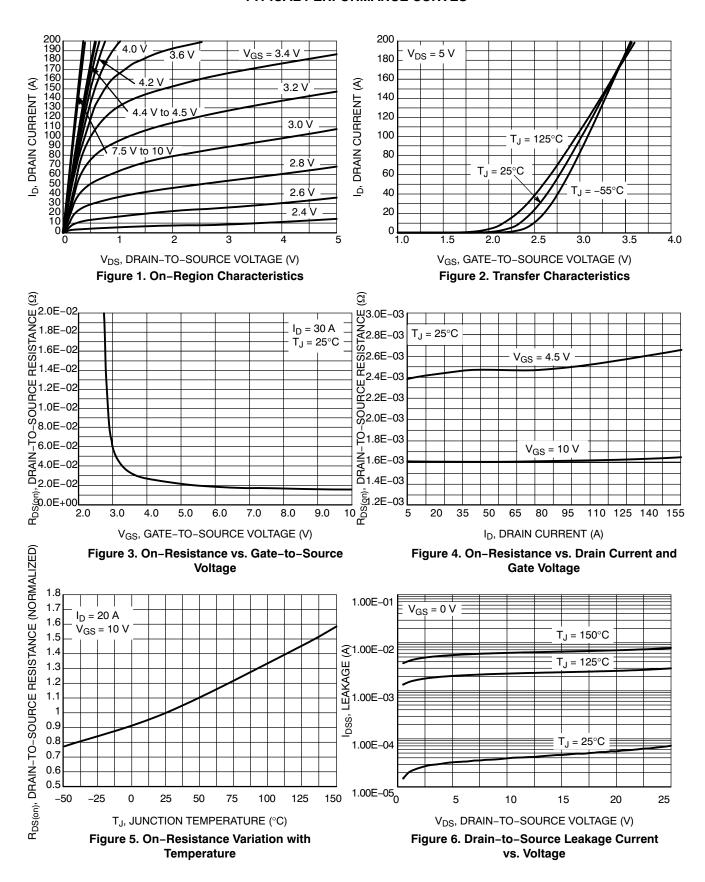
- 3. Pulse Test: pulse width \leq 300 μ s, duty cycle \leq 2%.
- 4. Switching characteristics are independent of operating junction temperatures.

ELECTRICAL CHARACTERISTICS ($T_J = 25^{\circ}C$ unless otherwise specified)

Parameter	Symbol	Test Condition		Min	Тур	Max	Unit
SWITCHING CHARACTERISTICS (No	ote 4)			•	•	•	
Turn-On Delay Time	t _{d(ON)}	V_{GS} = 10 V, V_{DS} = 15 V, I_{D} = 15 A, R_{G} = 3.0 Ω			9.4		ns ns
Rise Time	t _r				16.7		
Turn-Off Delay Time	t _{d(OFF)}				35.2		
Fall Time	t _f				7.4		
DRAIN-SOURCE DIODE CHARACTE	RISTICS				,		
Forward Diode Voltage	V _{SD}	$V_{GS} = 0 \text{ V},$ $I_{S} = 2 \text{ A}$ $T_{J} = 25^{\circ}\text{C}$ $T_{J} = 125^{\circ}\text{C}$		0.4	0.7	V	
			T _J = 125°C		0.32		1 °
Reverse Recovery Time	t _{RR}	$V_{GS} = 0 \text{ V, } dI_S/dt = 100 \text{ A/}\mu\text{s,}$ $I_S = 2 \text{ A}$			45		ns
Charge Time	ta				23		
Discharge Time	t _b				22		
Reverse Recovery Charge	Q _{RR}				50		nC
PACKAGE PARASITIC VALUES	-						
Source Inductance	L _S	T _A = 25°C			0.65		nH
Drain Inductance	L _D				0.20		
Gate Inductance	L _G				1.5		
Gate Resistance	R _G				1.0		Ω

Pulse Test: pulse width ≤ 300 μs, duty cycle ≤ 2%.
 Switching characteristics are independent of operating junction temperatures.

TYPICAL PERFORMANCE CURVES



TYPICAL PERFORMANCE CURVES

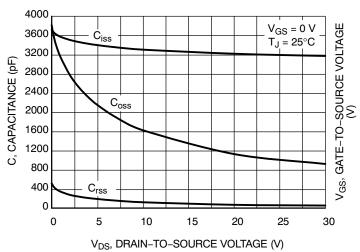


Figure 7. Capacitance Variation

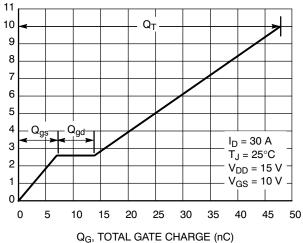


Figure 8. Gate-to-Source and
Drain-to-Source Voltage vs. Total Charge

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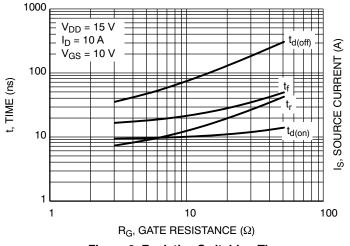


Figure 9. Resistive Switching Time Variation vs. Gate Resistance

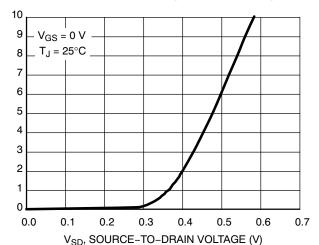


Figure 10. Diode Forward Voltage vs. Current

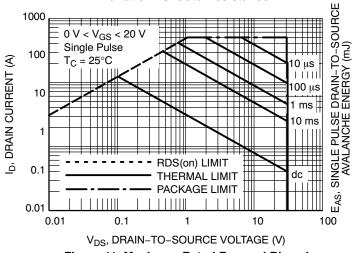


Figure 11. Maximum Rated Forward Biased Safe Operating Area

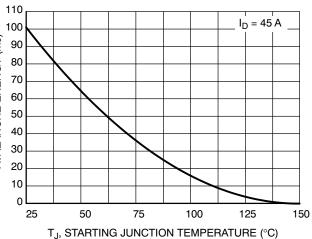


Figure 12. Maximum Avalanche Energy vs. Starting Junction Temperature

TYPICAL PERFORMANCE CURVES

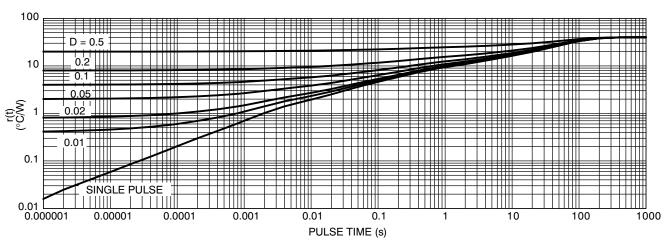
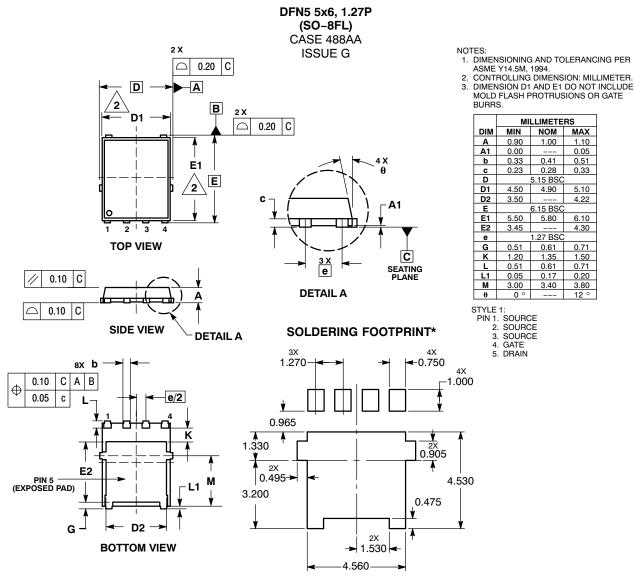


Figure 13. Thermal Response

PACKAGE DIMENSIONS



*For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

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